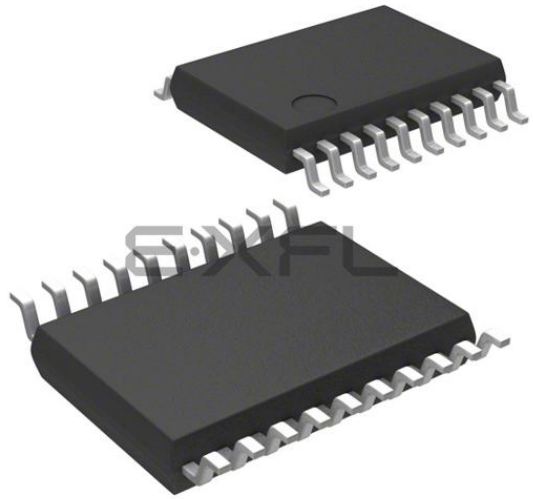

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, SPI, UART/USART, USB
Peripherals	DMA, POR, PWM, WDT
Number of I/O	15
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	2.4V ~ 3.6V
Data Converters	A/D 11x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	20-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	20-TSSOP
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f070f6p6

Contents

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3.4 Cyclic redundancy check calculation unit (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a configurable generator polynomial value and size.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

3.5 Power management

3.5.1 Power supply schemes

- V_{DD} = 2.4 to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through VDD pins.
- V_{DDA} = from V_{DD} to 3.6 V: external analog power supply for ADC, Reset blocks, RCs and PLL. The V_{DDA} voltage level must be always greater or equal to the V_{DD} voltage level and must be provided first.

For more details on how to connect power pins, refer to *Figure 9: Power supply scheme*.

3.5.2 Power supply supervisors

The device has integrated power-on reset (POR) and power-down reset (PDR) circuits. They are always active, and ensure proper operation above a threshold of 2 V. The device remains in reset mode when the monitored supply voltage is below a specified threshold, $V_{POR/PDR}$, without the need for an external reset circuit.

- The POR monitors only the V_{DD} supply voltage. During the startup phase it is required that V_{DDA} should arrive first and be greater than or equal to V_{DD}.
- The PDR monitors both the V_{DD} and V_{DDA} supply voltages, however the V_{DDA} power supply supervisor can be disabled (by programming a dedicated Option bit) to reduce the power consumption if the application design ensures that V_{DDA} is higher than or equal to V_{DD}.

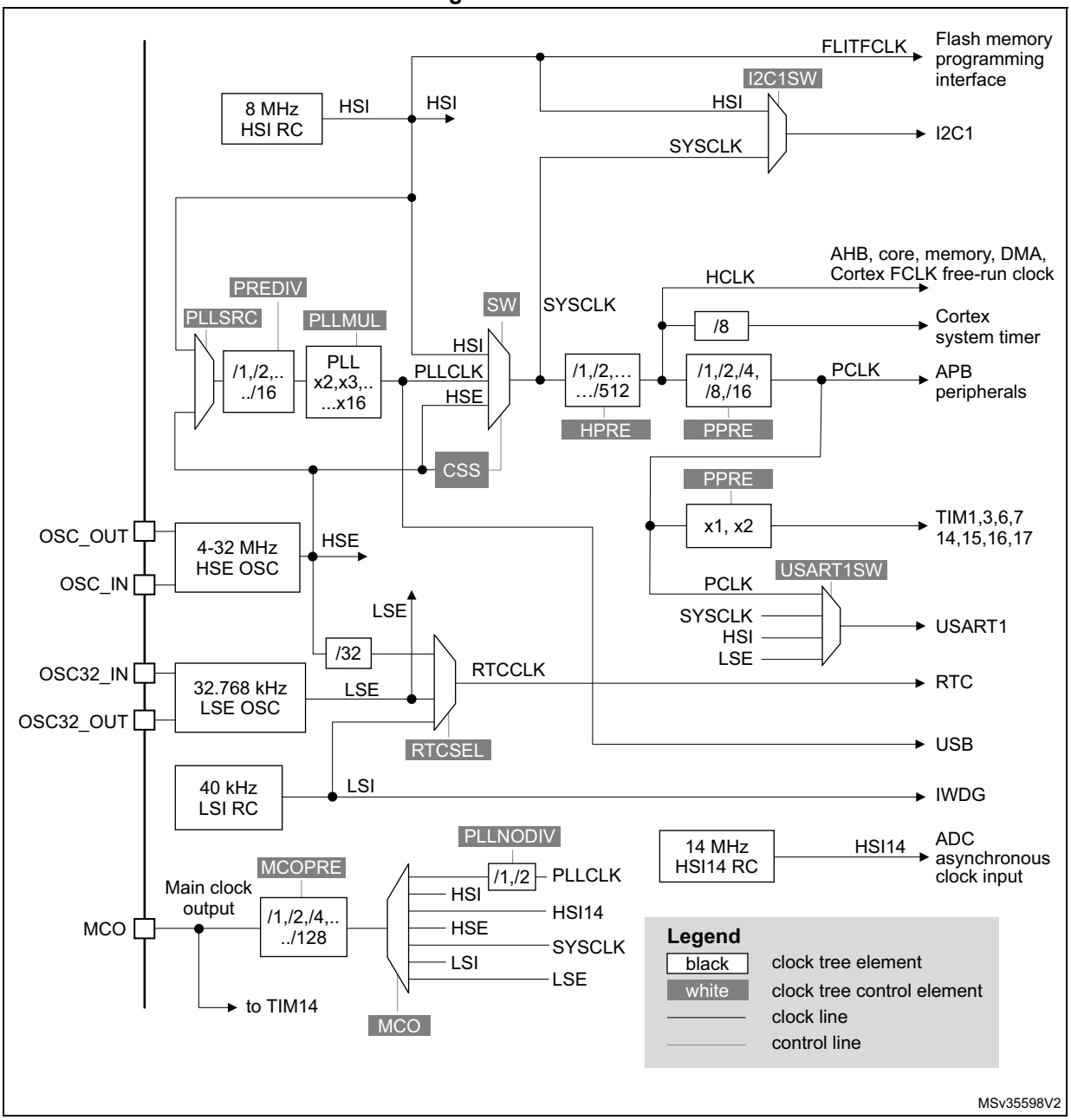
3.5.3 Voltage regulator

The regulator has two operating modes and it is always enabled after reset.

- Main (MR) is used in normal operating mode (Run).
- Low power (LPR) can be used in Stop mode where the power demand is reduced.

In Standby mode, it is put in power down mode. In this mode, the regulator output is in high impedance and the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost).

Figure 2. Clock tree



3.7 General-purpose inputs/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions.

The I/O configuration can be locked if needed following a specific sequence in order to avoid spurious writing to the I/Os registers.

3.13 Inter-integrated circuit interfaces (I^2C)

Up to two I2C interfaces (I2C1 and I2C2) can operate in multimaster or slave modes. Both can support Standard mode (up to 100 kbit/s) or Fast mode (up to 400 kbit/s). I2C1 also supports Fast Mode Plus (up to 1 Mbit/s), with 20 mA output drive.

Both support 7-bit and 10-bit addressing modes, multiple 7-bit slave addresses (two addresses, one with configurable mask). They also include programmable analog and digital noise filters.

Table 5. Comparison of I2C analog and digital filters

-	Analog filter	Digital filter
Pulse width of suppressed spikes	≥ 50 ns	Programmable length from 1 to 15 I2C peripheral clocks
Benefits	Available in Stop mode	1. Extra filtering capability vs. standard requirements. 2. Stable length
Drawbacks	Variations depending on temperature, voltage, process	-

In addition, I2C1 provides hardware support for SMBUS 2.0 and PMBUS 1.1: ARP capability, Host notify protocol, hardware CRC (PEC) generation/verification, timeouts verifications and ALERT protocol management.

The I2C interfaces can be served by the DMA controller.

Refer to *Table 6* for the differences between I2C1 and I2C2.

Table 6. STM32F070CB/RB/C6/F6 I^2C implementation(1)

I2C features	I2C1	I2C2(2)
7-bit addressing mode	X	X
10-bit addressing mode	X	X
Standard mode (up to 100 kbit/s)	X	X
Fast mode (up to 400 kbit/s)	X	X
Fast Mode Plus (up to 1 Mbit/s), with 20mA output drive I/Os	X	-
Independent clock	X	-
SMBus	X	-
Wakeup from STOP	-	-

1. X = supported.
2. Only available on STM32F070xB devices.

3.14 Universal synchronous/asynchronous receiver/transmitter (USART)

The device embeds up to four universal synchronous/asynchronous receivers/transmitters that communicate at speeds of up to 6 Mbit/s.

Table 7 gives an overview of features as implemented on the available USART interfaces. All USART interfaces can be served by the DMA controller.

Table 7. STM32F70x0 USART implementation(1)

USART modes/ features	STM32F070x6		STM32F070xB		
	USART1	USART2	USART1 USART2	USART3	USART4
Hardware flow control for modem	X	X	X	X	X
Continuous communication using DMA	X	X	X	X	-
Multiprocessor communication	X	X	X	X	X
Synchronous mode	X	X	X	X	X
Smartcard mode	-	-	-	-	-
Single-wire Half-duplex communication	X	X	X	X	X
IrDA SIR ENDEC block	-	-	-	-	-
LIN mode	-	-	-	-	-
Dual clock domain and wakeup from Stop mode	-	-	-	-	-
Receiver timeout interrupt	X	-	X	-	-
Modbus communication	-	-	-	-	-
Auto baud rate detection (supported modes)	4	-	4	-	-
Driver Enable	X	X	X	X	X
USART data length	7, 8 and 9 bits				

1. **X = supported.**

3.15 Serial peripheral interface (SPI)

Up to two SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

SPI1 and SPI2 are identical and implement the set of features shown in the following table.

Table 10. STM32F070xB/6 pin definitions (continued)

Pin numbers			Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	LQFP48	TSSOP20					Alternate functions	Additional functions
41	29	-	PA8	I/O	FT	-	USART1_CK, TIM1_CH1, EVENTOUT, MCO	-
42	30	17	PA9	I/O	FT	(4)	USART1_TX, TIM1_CH2, TIM15_BKIN, I2C1_SCL(3)	-
43	31	18	PA10	I/O	FT	-	USART1_RX, TIM1_CH3, TIM17_BKIN, I2C1_SDA(3)	-
44	32	17(5)	PA11	I/O	FT	-	USART1_CTS, TIM1_CH4, EVENTOUT	USB_DM
45	33	18(5)	PA12	I/O	FT	-	USART1_RTS, TIM1_ETR, EVENTOUT	USB_DP
46	34	19	PA13	I/O	FT	(6)	IR_OUT, SWDIO, USB_NOE	-
47	35	-	VSS	S	-	-	Ground	
48	36	-	VDD	S	-	-	Digital power supply	
49	37	20	PA14	I/O	FT	-	USART2_TX, SWCLK	-
50	38	-	PA15	I/O	FT	(4)	SPI1_NSS, USART2_RX, USART4_RTS, EVENTOUT	-
51	-	-	PC10	I/O	FT	(4)	USART3_TX, USART4_TX	-
52	-	-	PC11	I/O	FT	(4)	USART3_RX, USART4_RX	-
53	-	-	PC12	I/O	FT	(4)	USART3_CK, USART4_CK	-
54	-	-	PD2	I/O	FT	(4)	TIM3_ETR, USART3_RTS	-
55	39	-	PB3	I/O	FT	-	SPI1_SCK, EVENTOUT	-
56	40	-	PB4	I/O	FT	-	SPI1_MISO, TIM17_BKIN, TIM3_CH1, EVENTOUT	-
57	41	-	PB5	I/O	FT	(4)	SPI1_MOSI, I2C1_SMBA, TIM16_BKIN, TIM3_CH2	WKUP6
58	42	-	PB6	I/O	FTf	-	I2C1_SCL, USART1_TX, TIM16_CH1N	-

Table 16. STM32F070CB/RB/C6/F6 peripheral register boundary addresses (continued)

Bus	Boundary address	Size	Peripheral
APB	0x4000 7400 - 0x4000 7FFF	3 KB	Reserved
	0x4000 7000 - 0x4000 73FF	1 KB	PWR
	0x4000 6C00 - 0x4000 6FFF	1 KB	Reserved
	0x4000 6400 - 0x4000 67FF	2 KB	Reserved
	0x4000 6000 - 0x4000 63FF	1 KB	USB RAM
	0x4000 5800 - 0x4000 5BFF	1 KB	I2C2(1)
	0x4000 5400 - 0x4000 57FF	1 KB	I2C1
	0x4000 5000 - 0x4000 53FF	3 KB	Reserved
	0x4000 4C00 - 0x4000 4FFF	1 KB	USART4(1)
	0x4000 4800 - 0x4000 4BFF	1 KB	USART3(1)
	0x4000 4400 - 0x4000 47FF	1 KB	USART2
	0x4000 3C00 - 0x4000 43FF	2 KB	Reserved
	0x4000 3800 - 0x4000 3BFF	1 KB	SPI2(1)
	0x4000 3400 - 0x4000 37FF	1 KB	Reserved
	0x4000 3000 - 0x4000 33FF	1 KB	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 KB	WWDG
	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 2400 - 0x4000 27FF	1 KB	Reserved
	0x4000 2000 - 0x4000 23FF	1 KB	TIM14
	0x4000 1800 - 0x4000 1FFF	2 KB	Reserved
	0x4000 1400 - 0x4000 17FF	1 KB	TIM7
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0800 - 0x4000 0FFF	2 KB	Reserved
	0x4000 0400 - 0x4000 07FF	1 KB	TIM3
	0x4000 0000 - 0x4000 03FF	1 KB	Reserved

1. Available on STM32F070CB/RB devices only.

Table 18. Current characteristics

Symbol	Ratings	Max.	Unit
ΣI_{VDD}	Total current into sum of all VDD power lines (source)(1)	120	mA
ΣI_{VSS}	Total current out of sum of all VSS ground lines (sink)(1)	-120	
$I_{VDD(PIN)}$	Maximum current into each VDD power pin (source)(1)	100	
$I_{VSS(PIN)}$	Maximum current out of each VSS ground pin (sink)(1)	-100	
$I_{IO(PIN)}$	Output current sunk by any I/O and control pin	25	
	Output current source by any I/O and control pin	-25	
$\Sigma I_{IO(PIN)}$	Total output current sunk by sum of all I/Os and control pins(2)	80	
	Total output current sourced by sum of all I/Os and control pins(2)	-80	
$I_{INJ(PIN)}$(3)	Injected current on FT and FTf pins	-5/+0(4)	
	Injected current on TC and RST pin	± 5	
	Injected current on TTa pins(5)	± 5	
$\Sigma I_{INJ(PIN)}$	Total injected current (sum of all I/O and control pins)(6)	± 25	

1. All main power (VDD, VDDA) and ground (VSS, VSSA) pins must always be connected to the external power supply, in the permitted range.
2. This current consumption must be correctly distributed over all I/Os and control pins. The total output current must not be sunk/sourced between two consecutive power supply pins referring to high pin count QFP packages.
3. A positive injection is induced by $V_{IN} > V_{DDIOx}$ while a negative injection is induced by $V_{IN} < V_{SS}$. $I_{INJ(PIN)}$ must never be exceeded. Refer to *Table 17: Voltage characteristics* for the maximum allowed input voltage values.
4. Positive injection is not possible on these I/Os and does not occur for input voltages lower than the specified maximum value.
5. On these I/Os, a positive injection is induced by $V_{IN} > V_{DDA}$. Negative injection disturbs the analog performance of the device. See note (2) below *Table 51: ADC accuracy*.
6. When several inputs are submitted to a current injection, the maximum $\Sigma I_{INJ(PIN)}$ is the absolute sum of the positive and negative injected currents (instantaneous values).

Table 19. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	–65 to +150	°C
T_J	Maximum junction temperature	150	°C

6.3 Operating conditions

6.3.1 General operating conditions

Table 20. General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f_{HCLK}	Internal AHB clock frequency	-	0	48	MHz
f_{PCLK}	Internal APB clock frequency	-	0	48	
V_{DD}	Standard operating voltage	-	2.4	3.6	V

Table 32. HSE oscillator characteristics

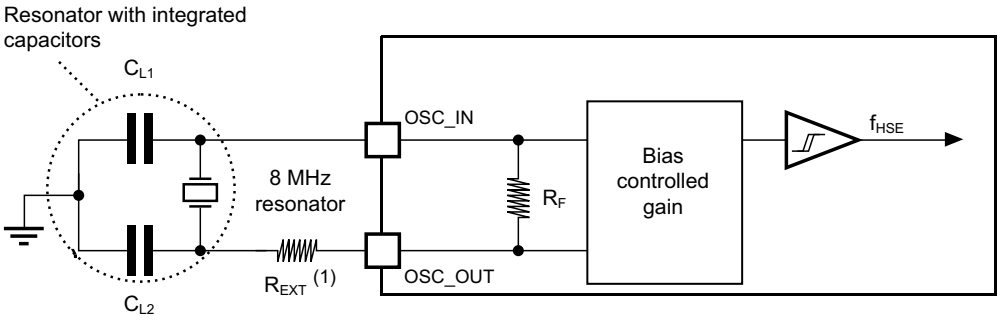
Symbol	Parameter	Conditions[1]	Min[2]	Typ	Max[2]	Unit
I_{DD}	HSE current consumption	During startup[3]	-	-	8.5	mA
		V_{DD} = 3.3 V, Rm = 45 Ω, CL = 10 pF@8 MHz	-	0.5	-	
		V_{DD} = 3.3 V, Rm = 30 Ω, CL = 20 pF@32 MHz	-	1.5	-	
g_m	Oscillator transconductance	Startup	10	-	-	mA/V
$t_{SU(HSE)}$[4]	Startup time	V_{DD} is stabilized	-	2	-	ms

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
2. Guaranteed by design, not tested in production.
3. This consumption level occurs during the first 2/3 of the $t_{SU(HSE)}$ startup time
4. $t_{SU(HSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

For C_{L1} and C_{L2}, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 20 pF range (Typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 13*). C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2}. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2}.

Note: For information on selecting the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Figure 13. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal resonator oscillator. All the information given in this paragraph are based on design simulation results

obtained with typical external components specified in *Table 33*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

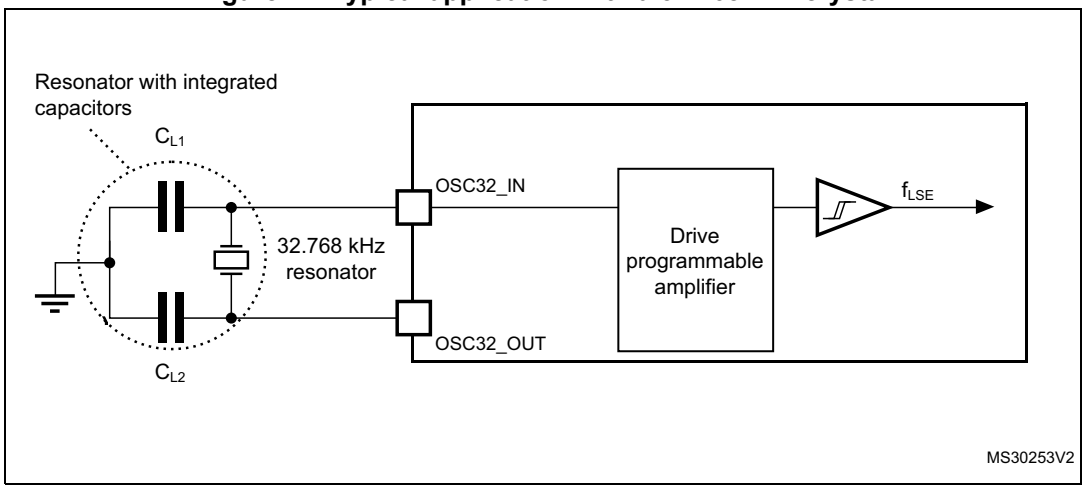
Table 33. LSE oscillator characteristics (f_{LSE} = 32.768 kHz)

Symbol	Parameter	Conditions(1)	Min(2)	Typ	Max(2)	Unit
I_{DD}	LSE current consumption	low drive capability	-	0.5	0.9	µA
		medium-low drive capability	-	-	1	
		medium-high drive capability	-	-	1.3	
		high drive capability	-	-	1.6	
g_m	Oscillator transconductance	low drive capability	5	-	-	µA/V
		medium-low drive capability	8	-	-	
		medium-high drive capability	15	-	-	
		high drive capability	25	-	-	
$t_{SU(LSE)}$(3)	Startup time	V_{DDIOx} is stabilized	-	2	-	s

1. Refer to the note and caution paragraphs below the table, and to the application note AN2867 “Oscillator design guide for ST microcontrollers”.
2. Guaranteed by design, not tested in production.
3. $t_{SU(LSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768 kHz oscillation is reached. This value is measured for a standard crystal and it can vary significantly with the crystal manufacturer

Note: For information on selecting the crystal, refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website www.st.com.

Figure 14. Typical application with a 32.768 kHz crystal



Note: An external resistor is not required between OSC32_IN and OSC32_OUT and it is forbidden to add one.

Table 36. LSI oscillator characteristics(1)

Symbol	Parameter	Min	Typ	Max	Unit
$t_{su(LSI)}$(2)	LSI oscillator startup time	-	-	85	µs
$I_{DDA(LSI)}$(2)	LSI oscillator power consumption	-	0.75	-	µA

1. V_{DDA} = 3.3 V, T_A = -40 to 85 °C unless otherwise specified.
2. Guaranteed by design, not tested in production.

6.3.9 PLL characteristics

The parameters given in *Table 37* are derived from tests performed under ambient temperature and supply voltage conditions summarized in *Table 20: General operating conditions*.

Table 37. PLL characteristics

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
f_{PLL_IN}	PLL input clock(1)	1(2)	8.0	24(2)	MHz
	PLL input clock duty cycle	40(2)	-	60(2)	%
f_{PLL_OUT}	PLL multiplier output clock	16(2)	-	48	MHz
t_{LOCK}	PLL lock time	-	-	200(2)	µs
$Jitter_{PLL}$	Cycle-to-cycle jitter	-	-	300(2)	ps

1. Take care to use the appropriate multiplier factors to obtain PLL input clock values compatible with the range defined by f_{PLL_OUT}.
2. Guaranteed by design, not tested in production.

6.3.10 Memory characteristics

Flash memory

The characteristics are given at T_A = -40 to 85 °C unless otherwise specified.

Table 38. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Typ	Max(1)	Unit
t_{prog}	16-bit programming time	T_A = -40 to +85 °C	-	53.5	-	µs
t_{ERASE}	Page erase time (2)	T_A = -40 to +85 °C	-	30	-	ms
t_{ME}	Mass erase time	T_A = -40 to +85 °C	-	30	-	ms
I_{DD}	Supply current	Write mode	-	-	10	mA
		Erase mode	-	-	12	mA
V_{prog}	Programming voltage	-	2.4	-	3.6	V

1. Guaranteed by design, not tested in production.
2. Page size is 1KB for STM32F070x6 devices and 2KB for STM32F070xB devices.

Table 44. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on BOOT0 and PF1 pins	-0	NA	mA
	Injected current on PA9, PB3, PB13, PF11 pins with induced leakage current on adjacent pins less than 50 µA	-5	NA	
	Injected current on PA11 and PA12 pins with induced leakage current on adjacent pins less than -1 mA	-5	NA	
	Injected current on all other FT and FTf pins	-5	NA	
	Injected current on PB0 and PB1 pins	-5	NA	
	Injected current on PC0 pin	-0	+5	
	Injected current on all other TTa, TC and RST pins	-5	+5	

6.3.14 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in *Table 45* are derived from tests performed under the conditions summarized in *Table 20: General operating conditions*. All I/Os are designed as CMOS- and TTL-compliant (except BOOT0).

Table 45. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IL}	Low level input voltage	TC and TTa I/O	-	-	$0.3\ V_{DDIOx}+0.07^{(1)}$	V
		FT and FTf I/O	-	-	$0.475\ V_{DDIOx}-0.2^{(1)}$	
		BOOT0	-	-	$0.3\ V_{DDIOx}-0.3^{(1)}$	
		All I/Os except BOOT0 pin	-	-	$0.3\ V_{DDIOx}$	
V_{IH}	High level input voltage	TC and TTa I/O	$0.445\ V_{DDIOx}+0.398^{(1)}$	-	-	V
		FT and FTf I/O	$0.5\ V_{DDIOx}+0.2^{(1)}$	-	-	
		BOOT0	$0.2\ V_{DDIOx}+0.95^{(1)}$	-	-	
		All I/Os except BOOT0 pin	$0.7\ V_{DDIOx}$	-	-	
V_{hys}	Schmitt trigger hysteresis	TC and TTa I/O	-	$200^{(1)}$	-	mV
		FT and FTf I/O	-	$100^{(1)}$	-	
		BOOT0	-	$300^{(1)}$	-	

Table 47. I/O AC characteristics(1)(2)

OSPEEDRy [1:0] value(1)	Symbol	Parameter	Conditions	Min	Max	Unit
x0	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF, $V_{DDIOx} \geq$ 2.4 V	-	2	MHz
	$t_{f(IO)out}$	Output fall time		-	125	ns
	$t_{r(IO)out}$	Output rise time		-	125	
01	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF, $V_{DDIOx} \geq$ 2.4 V	-	10	MHz
	$t_{f(IO)out}$	Output fall time		-	25	ns
	$t_{r(IO)out}$	Output rise time		-	25	
11	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 30 pF, $V_{DDIOx} \geq$ 2.7 V	-	50	MHz
			C_L = 50 pF, $V_{DDIOx} \geq$ 2.7 V	-	30	
			C_L = 50 pF, 2.4 V $\leq V_{DDIOx} <$ 2.7 V	-	20	
	$t_{f(IO)out}$	Output fall time	C_L = 30 pF, $V_{DDIOx} \geq$ 2.7 V	-	5	ns
			C_L = 50 pF, $V_{DDIOx} \geq$ 2.7 V	-	8	
			C_L = 50 pF, 2.4 V $\leq V_{DDIOx} <$ 2.7 V	-	12	
	$t_{r(IO)out}$	Output rise time	C_L = 30 pF, $V_{DDIOx} \geq$ 2.7 V	-	5	
			C_L = 50 pF, $V_{DDIOx} \geq$ 2.7 V	-	8	
			C_L = 50 pF, 2.4 V $\leq V_{DDIOx} <$ 2.7 V	-	12	
Fm+ configuration (4)	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF, $V_{DDIOx} \geq$ 2.4 V	-	2	MHz
	$t_{f(IO)out}$	Output fall time		-	12	ns
	$t_{r(IO)out}$	Output rise time		-	34	
-	t_{EXTIpw}	Pulse width of external signals detected by the EXTI controller	-	10	-	ns

1. The I/O speed is configured using the OSPEEDRx[1:0] bits. Refer to the STM32F0xxxx RM0360 reference manual for a description of GPIO Port configuration register.
2. Guaranteed by design, not tested in production.
3. The maximum frequency is defined in *Figure 17*.
4. When Fm+ configuration is set, the I/O speed control is bypassed. Refer to the STM32F0xxxx reference manual RM0360 for a detailed description of Fm+ I/O configuration.

Table 50. R_{AIN} max for f_{ADC} = 14 MHz

T_s (cycles)	t_S (µs)	R_{AIN} max (kΩ)(1)
1.5	0.11	0.4
7.5	0.54	5.9
13.5	0.96	11.4
28.5	2.04	25.2
41.5	2.96	37.2
55.5	3.96	50
71.5	5.11	NA
239.5	17.1	NA

1. Guaranteed by design, not tested in production.

Table 51. ADC accuracy(1)(2)(3)

Symbol	Parameter	Test conditions	Typ	Max(4)	Unit
ET	Total unadjusted error	f_{PCLK} = 48 MHz, f_{ADC} = 14 MHz, R_{AIN} < 10 kΩ V_{DDA} = 2.7 V to 3.6 V T_A = -40 to 85 °C	±3.3	±4	LSB
EO	Offset error		±1.9	±2.8	
EG	Gain error		±2.8	±3	
ED	Differential linearity error		±0.7	±1.3	
EL	Integral linearity error		±1.2	±1.7	

1. ADC DC accuracy values are measured after internal calibration.
2. ADC Accuracy vs. Negative Injection Current: Injecting negative current on any of the standard (non-robust) analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current.
   Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 6.3.14* does not affect the ADC accuracy.
3. Better performance may be achieved in restricted V_{DDA}, frequency and temperature ranges.
4. Data based on characterization results, not tested in production.

Table 54. IWDG min/max timeout period at 40 kHz (LSI)(1)

Prescaler divider	PR[2:0] bits	Min timeout RL[11:0]= 0x000	Max timeout RL[11:0]= 0xFFF	Unit
/4	0	0.1	409.6	ms
/8	1	0.2	819.2	
/16	2	0.4	1638.4	
/32	3	0.8	3276.8	
/64	4	1.6	6553.6	
/128	5	3.2	13107.2	
/256	6 or 7	6.4	26214.4	

1. These timings are given for a 40 kHz clock but the microcontroller internal RC frequency can vary from 30 to 60 kHz. Moreover, given an exact RC oscillator frequency, the exact timings still depend on the phasing of the APB interface clock versus the LSI clock so that there is always a full RC period of uncertainty.

Table 55. WWDG min/max timeout value at 48 MHz (PCLK)

Prescaler	WDGTB	Min timeout value	Max timeout value	Unit
1	0	0.0853	5.4613	ms
2	1	0.1706	10.9226	
4	2	0.3413	21.8453	
8	3	0.6826	43.6906	

6.3.19 Communication interfaces

I^2C interface characteristics

The I2C interface meets the timings requirements of the I^2C-bus specification and user manual rev. 03 for:

- Standard-mode (Sm): with a bit rate up to 100 kbit/s
- Fast-mode (Fm): with a bit rate up to 400 kbit/s
- Fast-mode Plus (Fm+): with a bit rate up to 1 Mbit/s.

The I2C timings requirements are guaranteed by design when the I2C peripheral is properly configured (refer to Reference manual).

The SDA and SCL I/O requirements are met with the following restrictions: the SDA and SCL I/O pins are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DDIOx} is disabled, but is still present. Only FTf I/O pins support Fm+ low level output current maximum requirement. Refer to *Section 6.3.14: I/O port characteristics* for the I2C I/Os characteristics.

All I2C SDA and SCL I/Os embed an analog filter. Refer to the table below for the analog filter characteristics:

Figure 21. SPI timing diagram - slave mode and CPHA = 0

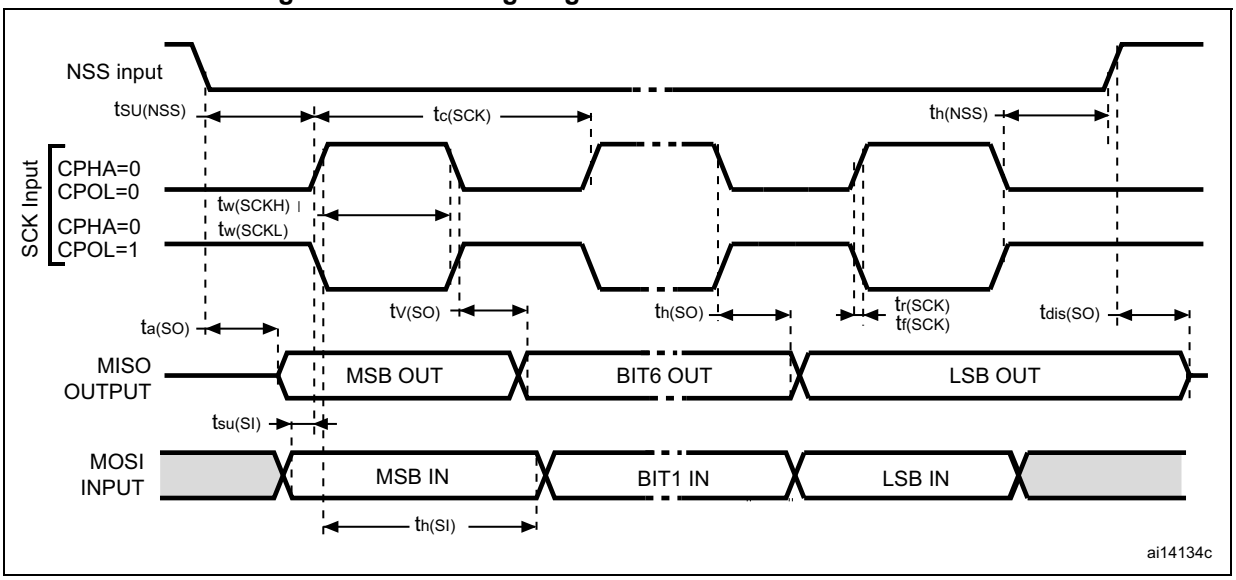
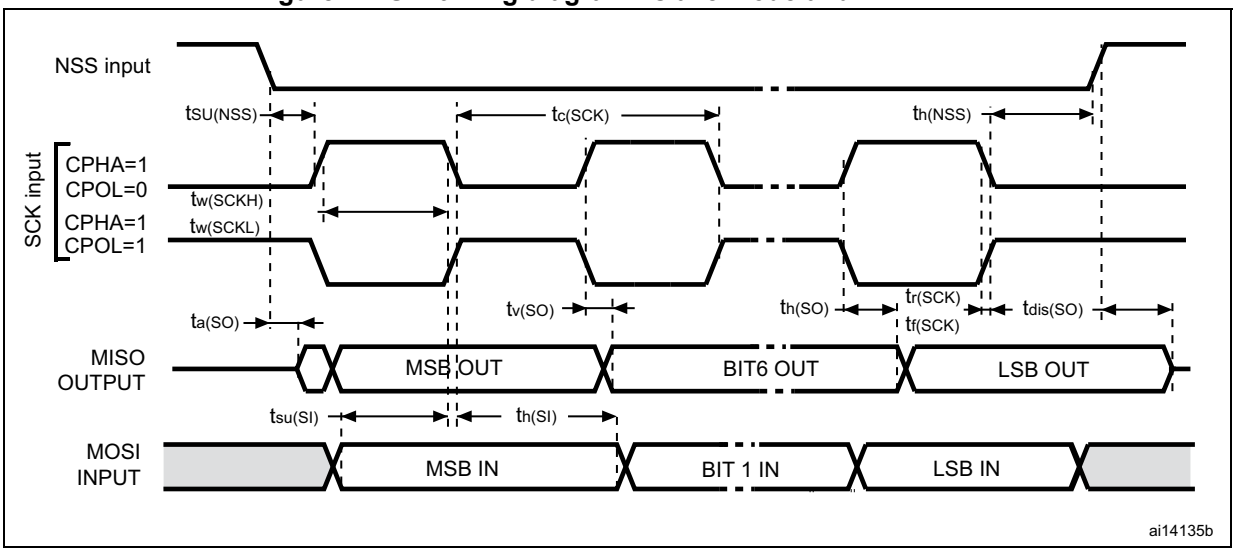


Figure 22. SPI timing diagram - slave mode and CPHA = 1



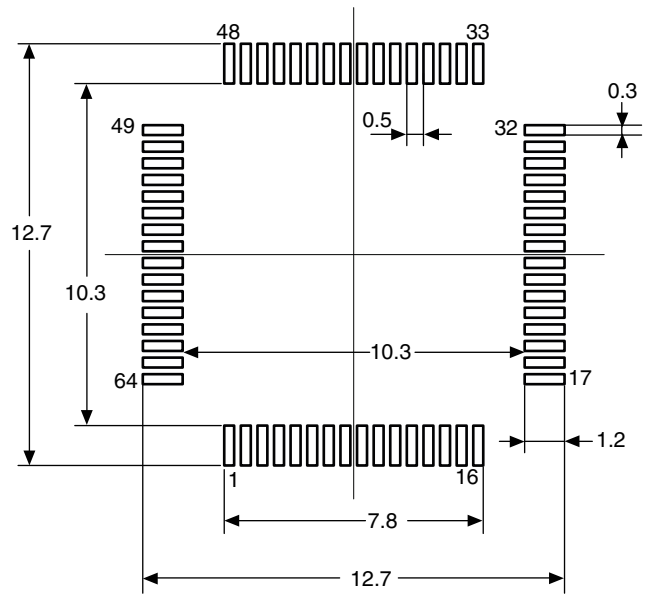
1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Table 59. LQFP64 mechanical data (continued)

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 25. LQFP64 recommended footprint



1. Dimensions are expressed in millimeters.

Table 64. Document revision history (continued)

Date	Revision	Changes
07-Feb-2016	3	– *Figure 15* and *Figure 16* improved – *Section 7: Package information* name and structure *change* – *Section 8: Ordering information* renamed from Part numbering; removed undue code sizes